PW PACKAGE (TOP VIEW)

AGND

V_{CC} 🛭 2

1Y0 🛮 3

1Y1 1Y2

GND

24

23

15

CLK

AV_{CC}

2Y3

□ v_{cc} 2G 14 13 **∏** FBIN

- Use CDCVF2509A as a Replacement for this Device
- Designed to Meet PC SDRAM Registered **DIMM Design Support Document Rev. 1.2**
- **Spread Spectrum Clock Compatible**
- Operating Frequency 25 MHz to 125 MHz
- Static tPhase Error Distribution at 66MHz to 100 MHz is ±150 ps
- Drop-In Replacement for TI CDC2509A With **Enhanced Performance**
- Jitter (cyc cyc) at 66 MHz to 100 MHz is

- FBOU

 Applications

 Applications

 Applications

 Applications

 Separate One Clock Input to One Bank of Five and One Bank of Four Outputs

 Separate Output Enable for Each Output Bank

 External Feedback (FBIN) Terminal Is Used to Synchronize the Outputs to the Clock input

 On-Chip Series Damping Resistors to External RC Network requires perates at 3.3 V

 tion

description

The CDC2509Ch a high-performance, low-skew, low-jitter, phase-lock loop (PLL) clock driver. It uses a PLL to precisely a ign, in both frequency and phase, the feedback (FBOUT) output to the clock (CLK) input signal. It is specifically designed for use with synchronous DRAMs. The CDC2509C operates at 3.3 V $_{\rm CC}$. It also provides integrated series-damping resistors that make it ideal for driving point-to-point loads.

One bank of five outputs and one bank of four outputs provide nine low-skew, low-jitter copies of CLK. Output signal duty cycles are adjusted to 50%, independent of the duty cycle at CLK. Each bank of outputs is enabled or disabled separately via the control (1G and 2G) inputs. When the G inputs are high, the outputs switch in phase and frequency with CLK; when the G inputs are low, the outputs are disabled to the logic-low state.

Unlike many products containing PLLs, the CDC2509C does not require external RC networks. The loop filter for the PLL is included on-chip, minimizing component count, board space, and cost.

Because it is based on PLL circuitry, the CDC2509C requires a stabilization time to achieve phase lock of the feedback signal to the reference signal. This stabilization time is required, following power up and application of a fixed-frequency, fixed-phase signal at CLK, and following any changes to the PLL reference or feedback signals. The PLL can be bypassed for test purposes by strapping AV_{CC} to ground.

The CDC2509C is characterized for operation from 0°C to 85°C.



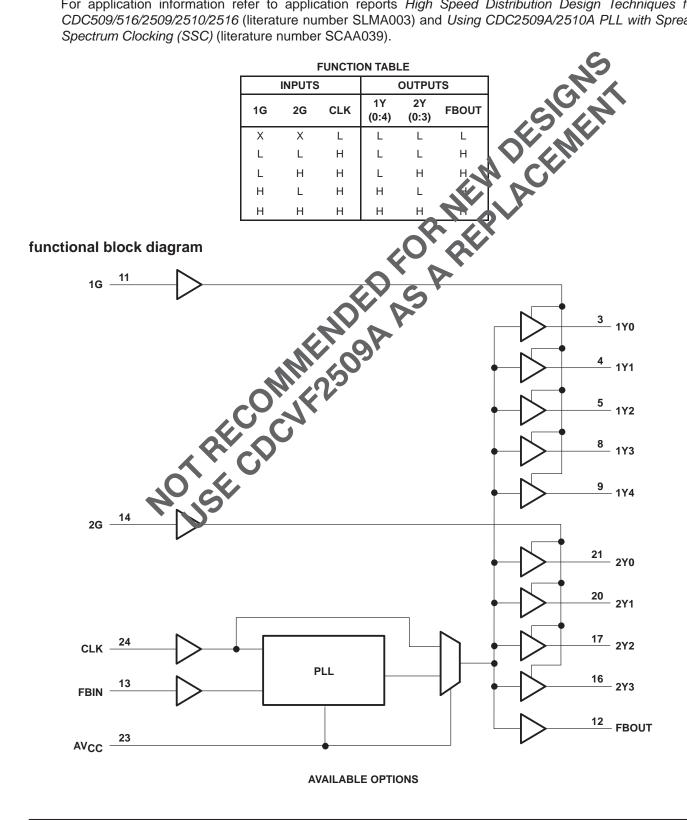
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STRUMENTS

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description (continued)

For application information refer to application reports High Speed Distribution Design Techniques for CDC509/516/2509/2510/2516 (literature number SLMA003) and Using CDC2509A/2510A PLL with Spread Spectrum Clocking (SSC) (literature number SCAA039).





SCAS620A - DECEMBER 1998 - REVISED DECEMBER 2004

	PACKAGE
TA	SMALL OUTLINE (PW)
0°C to 85°C	CDC2509CPWR

Terminal Functions

TEI	RMINAL	T\/DE	DECODER OF A
NAME	NO.	TYPE	DESCRIPTION
CLK	24	ı	Clock input. CLK provides the clock signal to be distributed by the CDC F09C clock driver. CLK is used to provide the reference signal to the integrated PLL that the creates the clock output signals. CLK must have a fixed frequency and fixed phase for the PLL to bt lin phase lock. Once the circuit is powered up and a valid CLK signal is applied, a stabilization time is nearlied for the PLL to phase lock the feedback signal to its reference signal.
FBIN	13	I	Feedback input. FBIN provides the feedback small to the internal PLL. FBIN must be hard-wired to FBOUT to complete the PLL. The integrated PLL synchronizes CLK and FBIN so that there is nominally zero phase error between CLK and FBIN.
1G	11	I	Output bank enable. 1G is the output enable by autputs 1Y(0:4). When 1G is low, outputs 1Y(0:4) are disabled to a logic-low state. When 4G is high, all outputs 1Y(0:4) are enabled and switch at the same frequency as CLK.
2G	14	1	Output bank enable. 20 is 15 output enable for outputs 2Y(0:3). When 2G is low, outputs 2Y(0:3) are disabled to a logic lows, at2. When 2G is high, all outputs 2Y(0:3) are enabled and switch at the same frequency as CLK.
FBOUT	12	0	Feedback output TBOUT's indicated for external feedback. It switches at the same frequency as CLK. When extendity wire (t) IBIN, FBOUT completes the feedback loop of the PLL. FBOUT has an integrated 1.5 22 ser as damping resistor.
1Y (0:4)	3, 4, 5, 8, 9	0	Clock a truts. These outputs provide low-skew copies of CLK. Output bank 1Y(0:4) is enabled via the 1C in ut. These patputs can be disabled to a logic-low state by deasserting the 1G control input. Each cutruit has a sintegrated 25- Ω series-damping resistor.
2Y (0:3)	21, 20, 17, 16		clock outputs. These outputs provide low-skew copies of CLK. Output bank 2Y(0:3) is enabled via the 2C in Ω . These outputs can be disabled to a logic-low state by deasserting the 2G control input. Each of to it has an integrated 25- Ω series-damping resistor.
AVCC	23	Pewer	Analog power supply. AV _{CC} provides the power reference for the analog circuitry. In addition, AV _{CC} can be used to bypass the PLL for test purposes. When AV _{CC} is strapped to ground, PLL is bypassed and CLK is buffered directly to the device outputs.
AGND	1	Ground	Analog ground. AGND provides the ground reference for the analog circuitry.
Vcc	2, 10, 15, 22	Power	Power supply
GND	6, 7, 18, 19	Ground	Ground

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, AV _{CC} (see Note 1)	
Input voltage range, V _I (see Note 2)	
Voltage range applied to any output in the high or low state,	Co
V _O (see Notes 2 and 3)	6 5 V to V _{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$)	-50 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through each V _{CC} or GND	±100 mA
Maximum power dissipation at $I_A = 55^{\circ}$ C (in still air) (see Note 4)	
Storage temperature range, T _{stq}	−65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent dam to to the covine. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicate to der "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device a condition.

- NOTES: 1. AV_{CC} must not exceed V_{CC}.
 - 2. The input and output negative-voltage ratings may be exceeded if an input and output clamp-current ratings are observed.
 - 3. This value is limited to 4.6 V maximum.
 - The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.
 For more information, refer to the *Package Thermal Considerations* application note in the *ABT Advanced BiCMOS Technology Data Book*, literature number SCBD002.

recommended operating conditions (see Note 5)

		MIN	MAX	UNIT
V _{CC} , AV _{CC}	Supply voltage	3	3.6	V
VIH	High-level input voltage	2		V
V _{IL}	Low-level input voltage		8.0	V
VI	Input voltage	0	VCC	V
loн	High-level output current		-12	mA
loL	Low-level output current		12	mA
TA	Operating free cir temperature	0	85	°C

NOTE 5: Unused inputs must be held high or low to prevent them from floating.

timing requirements over recommended ranges of supply voltage and operating free-air temperature

		MIN	MAX	UNIT
f _{clk}	Clock frequency	25	125	MHz
	Input clock duty cycle	40%	60%	
	Stabilization time [†]		1	ms

[†] Time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal. For phase lock to be obtained, a fixed-frequency, fixed-phase reference signal must be present at CLK. Until phase lock is obtained, the specifications for propagation delay, skew, and jitter parameters given in the switching characteristics table are not applicable. This parameter does not apply for input modulation under SSC application.



electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V _{CC} , AV _{CC}	MIN	TYP‡	MAX	UNIT
VIK	Input clamp voltage	I _I = -18 mA	3 V			-1.2	V
		$I_{OH} = -100 \mu\text{A}$	MIN to MAX	V _{CC} -0.2	P.		
Vон	High-level output voltage	$I_{OH} = -12 \text{ mA}$	3 V	2.1	9		V
		$I_{OH} = -6 \text{ mA}$	3 V	2,4	`		
		I _{OL} = 100 μA	MIN to MAX		7,	0.2	
V_{OL}	Low-level output voltage	I _{OL} = 12 mA	3 V	0 4		0.8	V
		I _{OL} = 6 mA	34			0.55	
		V _O = 1 V	3.135	-32			
loH	High-level output current	$V_0 = 1.65 \text{ V}$	2.3 V		-36		mA
		$V_{O} = 3.135 \text{ V}$	8.465 ₩			-12	
		V _O = 1.95 V	243	34			
lOL	Low-level output current	V _O = 1.65 V	3.3 V		40		mA
		V _O = 0.4 V	3.465 V			14	
lį	Input current	V _I = V _{CC} or GND	3.6 V			±5	μΑ
I _{CC} §	Supply current	V _I = V _{CC} or GND, Outputs: low or high	3.6 V			10	μΑ
ΔlCC	Change in supply current	One input at V > 0.6 V, Other inputs () C or SND	3.3 V to 3.6 V			500	μΑ
Ci	Input capacitance	VI = VGC (ND	3.3 V		4		pF
Со	Output capacitance	VO = 100 or CNL	3.3 V		6		pF

[‡] For conditions shown as MIN or MAX, use us appropriate value specified under recommended operating conditions. § For I_{CC} of AV_{CC}, and I_{CC} vs Frequence (see Fig. 42 × 1 and 12).

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L=30~\rm pF$ (see Note 6 and Figures 1 and 2).

	PARAMETER	FROM	TO		AV _{CC} = 3 0.165 V	3.3 V	UNIT
		(INPUT)/CONDITION	(OUTPUT)	MIN	TYP	MAX	
	Phase error time static (normalized) (See Figures 3 – 2)	CLKIN↑ = 66 MHz to100 MHz	FBIN↑	-150		150	ps
tsk(o)	Output skew time§	Any Y or FBOUT	Any Y or FBOUT			200	ps
	Phase error time – jitter (see Note 7)		Any Y or FBOUT	-50		50	
	Jitter(cycle-cycle) (See Figures 9 and 10)	Clkin = 66 MHz to 100 MHz	Any Y or FBOUT			100	ps
	Duty cycle	F(clkin > 60 MHz)	Any Y or FBOUT	45%		55%	
t _r	Rise time (See Notes 8 and 9)	V _O = 1.2 V to 1.8 V, IBIS simulation	Any Y or FBOUT	2.5		1	V/ns
t _f	Fall time (See Notes 8 and 9)	$V_O = 1.2 \text{ V to } 1.8 \text{ V},$ IBIS simulation	Any Y or FBOUT	2.5		1	V/ns

[‡]These parameters are not production tested.

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[§] The $t_{Sk(0)}$ specification is only valid for equal loading of all outputs.

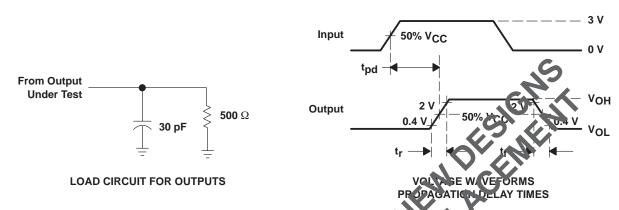
NOTES: `6. The specifications for parameters in this table are applicable only after any appropriate stabilization time has elapsed.

^{7.} Calculated per PC DRAM SPEC (tphase error, static – jitter(cycle-to-cycle)).

^{8.} This is equivalent to 0.8 ns/2.5 ns and 0.8 ns/2.7 ns into standard 500 Ω / 30 pf load for output swing of 04. V to 2 V.

^{9. 64} MB DIMM configuration according to PC SDRAM Registered DIMM Design Support Document, Figure 20 and Table 13.

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characters 100 MHz, Z_O = 50 Ω, t_r ≤ 1.2 ns, t_f ≤ 1.2 ns.
- C. The outputs are measured one at a time with one transition per n

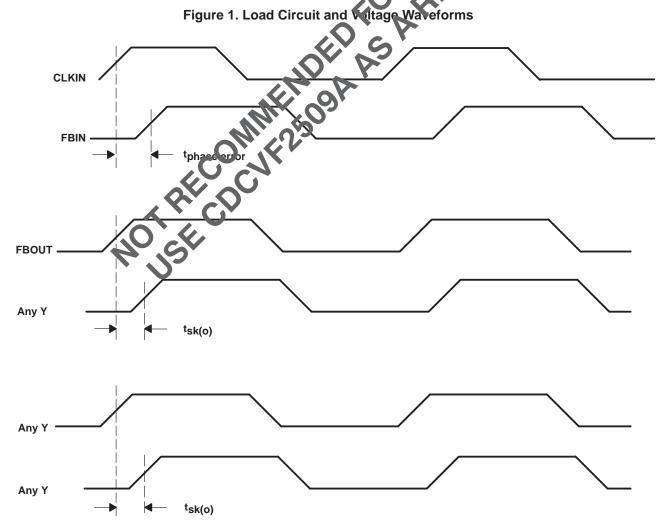
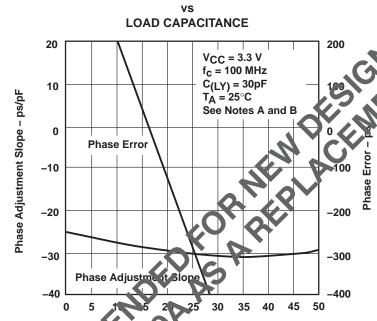


Figure 2. Phase Error and Skew Calculations



CDC2509C PHASE ADJUSTMENT SLOPE AND PHASE ERROR



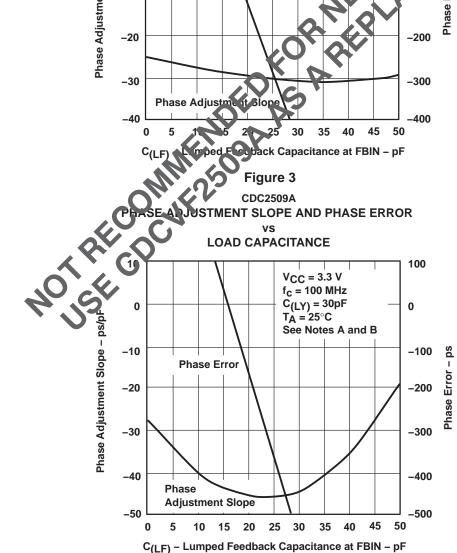
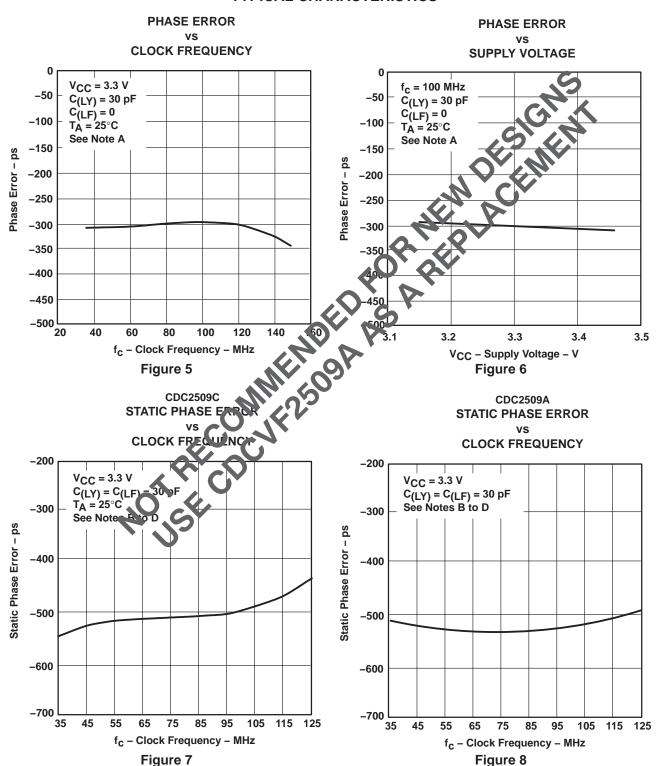


Figure 4

NOTES: A. Trace feedback length FBOUT to FBIN = 5 mm, Z_{O} = 50 Ω Phase error measured from CLK to Y

B. CLF = Lumped feedback capacitance at FBIN

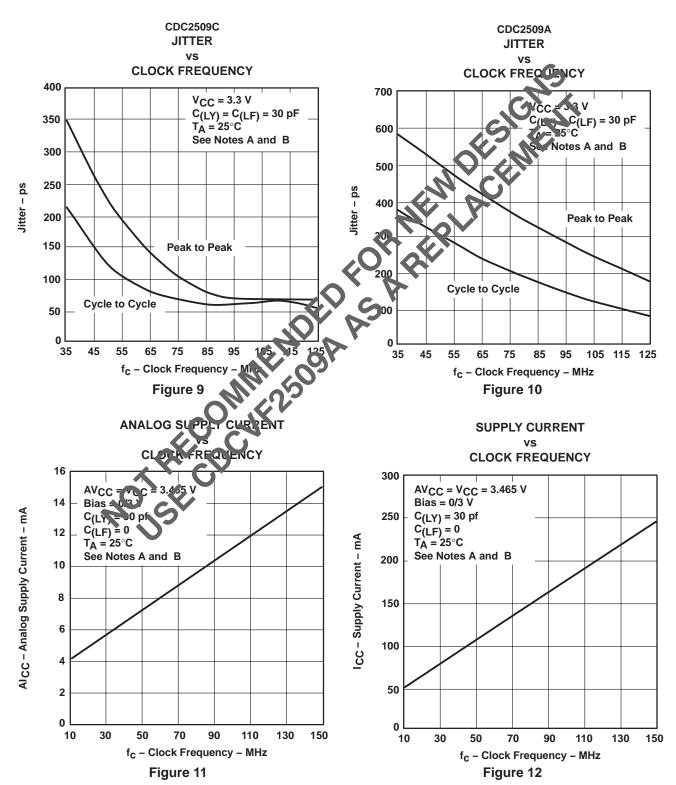




NOTES: A. Trace feedback length FBOUT to FBIN = 5 mm, Z_O = 50 Ω

- B. Phase error measured from CLK to FBIN
- C. CLY = Lumped capacitive load at Y
- D. CLF = Lumped feedback capacitance at FBIN

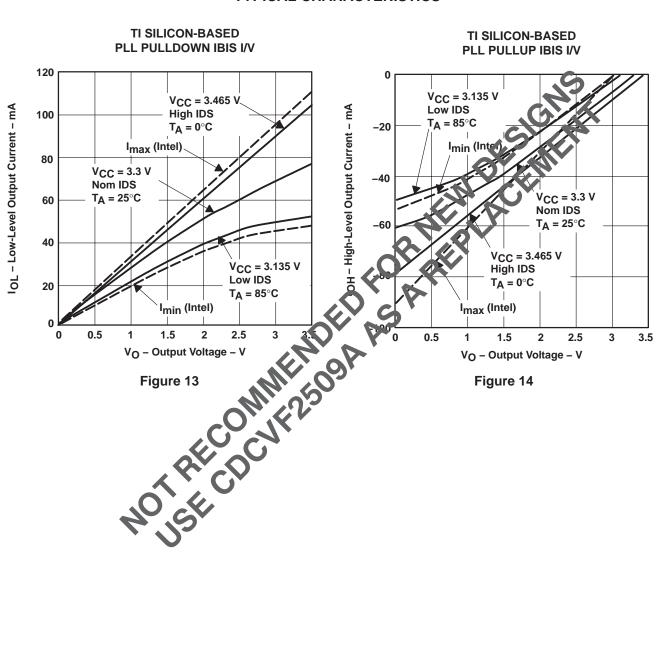




NOTES: A. C_(LY) = Lumped capacitive load at Y

B. $C_{(LF)} = Lumped$ feedback capacitance at FBIN





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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
CDC2509CPW	NRND	Production	TSSOP (PW) 24	60 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-	CK2509C
CDC2509CPW.B	NRND	Production	TSSOP (PW) 24	60 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	See CDC2509CPW	CK2509C
CDC2509CPWR	NRND	Production	TSSOP (PW) 24	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-	CK2509C
CDC2509CPWR.B	NRND	Production	TSSOP (PW) 24	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	See CDC2509CPWR	CK2509C

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

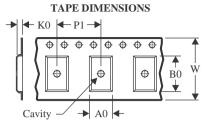
⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

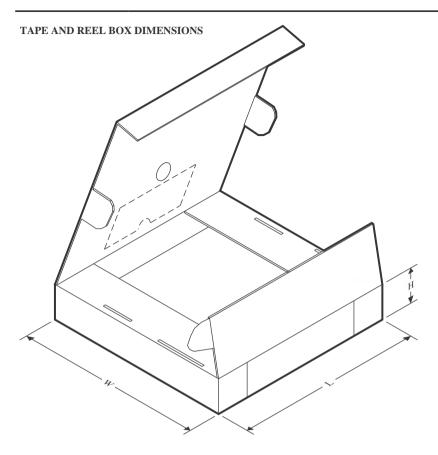


*All dimensions are nominal

	Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
L	CDC2509CPWR	TSSOP	PW	24	2000	330.0	16.4	6.95	8.3	1.6	8.0	16.0	Q1

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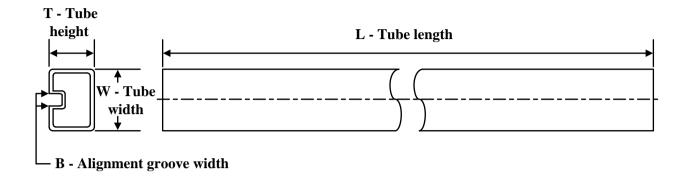
*All dimensions are nominal

Ì	Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ı	CDC2509CPWR	TSSOP	PW	24	2000	353.0	353.0	32.0

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TUBE

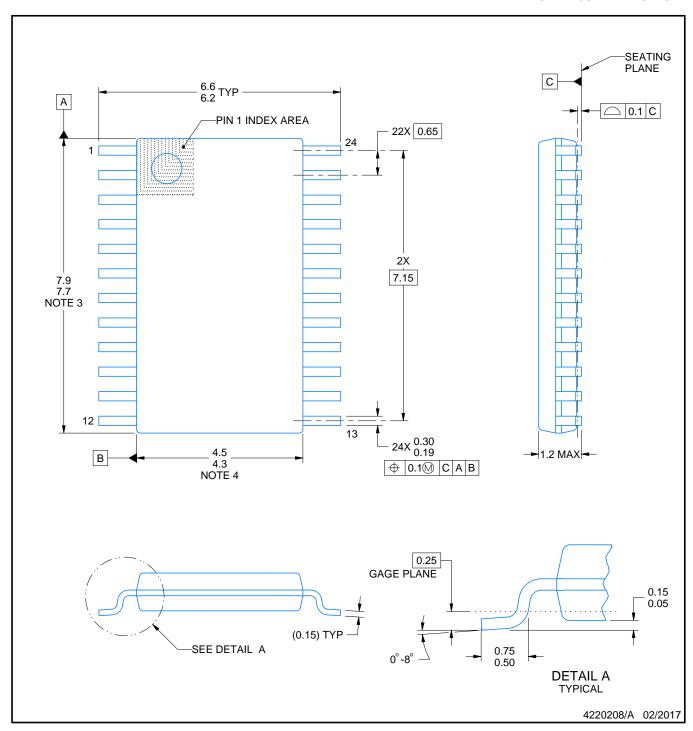


*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
CDC2509CPW	PW	TSSOP	24	60	530	10.2	3600	3.5
CDC2509CPW.B	PW	TSSOP	24	60	530	10.2	3600	3.5



SMALL OUTLINE PACKAGE



NOTES:

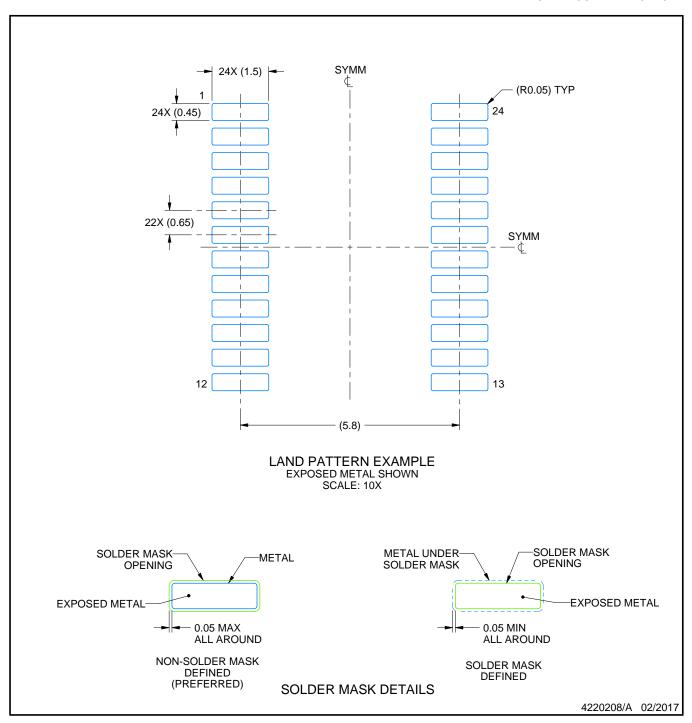
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



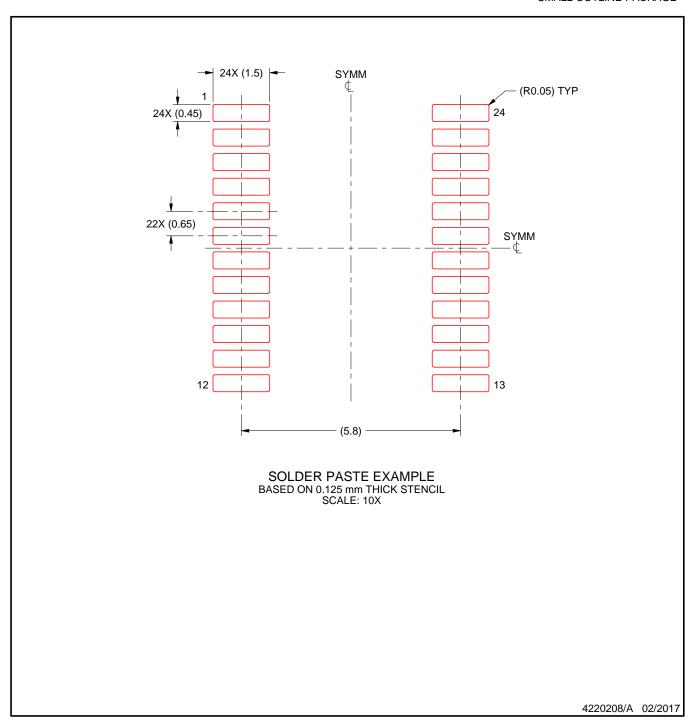
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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